

10/030123

FILED UNDER 35 U.S.C. 371

PATENT NUMBER and
ISSUE DATE

U.S. UTILITY Patent Application

APPL NUM	FILING DATE	CLASS	SUBCLASS	GAU	EXAMINER
10030123	05/16/2002	438	719	2812	<i>ZBL</i> <i>Stephen Greene</i>

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**CONTINUING DATA VERIFIED:

THIS APPLICATION IS A 371 OF PCT/JP01/04438 05/26/2001

** FOREIGN APPLICATIONS VERIFIED:*✓*

JAPAN 2000-156876 05/26/2000

PG-PUB	DO NOT PUBLISH <input type="checkbox"/>	RESCIND <input type="checkbox"/>	
Foreign priority claimed 35 USC 119 conditions met Verified and Acknowledged Examiner's initials <i>[initials]</i>		<input checked="" type="checkbox"/> yes <input type="checkbox"/> no <input checked="" type="checkbox"/> yes <input type="checkbox"/> no	ATTORNEY DOCKET NO 218478US2PCT
TITLE : Semiconductor manufacturing and inspecting device			

U.S. DEPT. OF COMM./PAT. & TM-PTO-436L(Rev. 12-94)

NOTICE OF ALLOWANCE MAILED		Assistant Examiner	CLAIMS ALLOWED	
			Total Claims	Print Claim for O.G
ISSUE FEE		DRAWING		
Amount Due	Date Paid	Sheets Drwg.	Figs.Drwg.	Print Fig.
		Primary Examiner		
		PREPARED FOR ISSUE		
		Application Examiner		
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